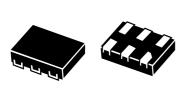


4 pin Smart Reset™

Datasheet - production data



UDFN6 (1.00 x 1.45 mm)

Applications

- Wearable
- Activity tracker
- Smartwatch
- Smartglasses

Features

- Operating voltage range 2 V to 5.5 V
- Low supply current 1 μA
- Integrated test mode
- Single Smart Reset[™] push-button input with fixed extended reset setup delay (t_{SRC}) from 0.5 s to 10 s in 0.5 s steps (typ.), option with internal input pull-up resistor
- Push-button controlled reset pulse duration
 - Option 1: fully push-button controlled, no fixed or minimum pulse width guaranteed
 - Option 2: defined output reset pulse duration (t_{REC}), factory-programmed
- Single reset output
 - Active low or active high
 - Push-pull or open drain with optional pullup resistor
- Fixed Smart Reset input logic voltage levels
- Operating temperature: -40 °C to +85 °C
- UDFN6 package 1.00 mm x 1.45 mm
- ECOPACK[®]2 (RoHS compliant, Halogen-Free)

Contents SR1

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SR1 Description

1 Description

The Smart ResetTM devices provide a useful feature which ensures that inadvertent short reset push-button closures do not cause system resets. This is done by implementing an extended Smart Reset input delay time (t_{SRC}), which ensures a safe reset and eliminates the need for a specific dedicated reset button.

This reset configuration provides versatility and allows the application to distinguish between a software generated interrupt and a hard system reset. When the input push-button is connected to the microcontroller interrupt input, and is closed for a short time, the processor can only be interrupted. If the system still does not respond properly, continuing to keep the push-button closed for the extended setup time t_{SRC} causes a hard reset of the processor through the reset output.

The SR1 has one Smart Reset input (\overline{SR}) with preset delayed Smart Reset setup time (t_{SRC}). The reset output (RST) is asserted after the Smart Reset input is held active for the selected t_{SRC} delay time. The RST output remains asserted either until the \overline{SR} input goes to inactive logic level (i.e. neither fixed nor minimum reset pulse width is set) or the output reset pulse duration is fixed for t_{REC} (i.e. factory-programmed). The device fully operates over a broad V_{CC} range from 2.0 V to 5.5 V.

1.1 Test mode

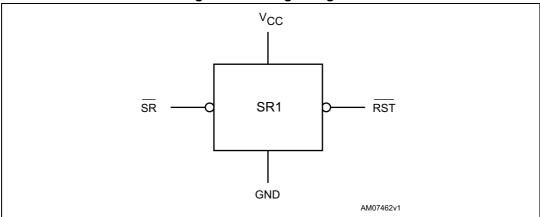
After pulling \overline{SR} up to V_{TEST} (V_{CC} + 1.4 V) or above, the counter starts to count the initial shortened $t_{SRC-INI}$ (42 ms, typ.). After $t_{SRC-INI}$ expires, the \overline{RST} output either goes down for t_{REC} (if t_{REC} option is used) or stays low as long as overvoltage on \overline{SR} is detected (if t_{REC} option is not used). This is feedback, and the user only knows that the device is locked in test mode. Each time the \overline{SR} input is connected to ground in test mode, a shortened $t_{SRC-SHORT}$ ($t_{SRC}/128$) is used instead of regular t_{SRC} (0.5 s - 10 s). In this way the device can be quickly tested without repeating test mode triggering. Return to normal mode is possible by performing a new startup of the device (i.e. V_{CC} goes to 0 V and back to its original state).

The advantages of this solution are its high glitch immunity, user feedback regarding entry into test mode, and testability within the full V_{CC} range.

Description SR1

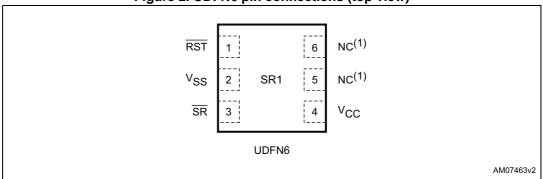
1.2 Logic diagram

Figure 1. SR1 logic diagram



1.3 Pin connections

Figure 2. UDFN6 pin connections (top view)



1. Not connected (not bonded); should be connected to V_{SS} .

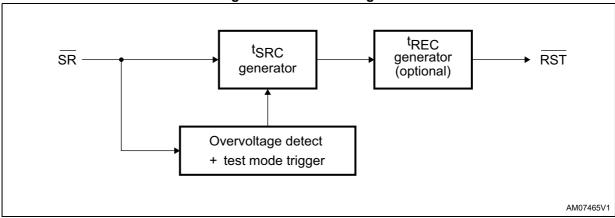
SR1 Device overview

2 Device overview

Table 1. Signal names

Pin n°	Name	Туре	Description	
1	RST	Output	Reset output, active low, open drain.	
2	V _{SS}	Supply ground Ground		
3	SR	Input	Smart Reset input, active low.	
4	V _{CC}	Supply voltage	Positive supply voltage for the device. A 0.1 μF decoupling ceramic capacitor is recommended to be connected between V_{CC} and V_{SS} pins.	
5	NC	- Not connected (not bonded); should be connected to V _S		
6	NC	-	Not connected (not bonded); should be connected to V _{SS} .	

Figure 3. SR1 block diagram



Pin descriptions SR1

3 Pin descriptions

3.1 Power supply (V_{CC})

This pin is used to provide power to the Smart Reset device. A 0.1 μ F ceramic decoupling capacitor is recommended to be connected between the V_{CC} and V_{SS} pins, as close to the SR1 device as possible.

3.2 Power-up sequence

In normal mode, if different input side (\overline{SR}) and V_{CC} voltage domains are used, power-on sequence must avoid meeting the test mode entry condition to avoid inadvertent test mode entry: there should not be logic high present on the \overline{SR} input before the V_{CC} power-up. However V_{CC} and $V(\overline{SR})$ rising at the same time is OK (e.g. if both are in the same voltage domain), the device will then safely start into normal operating mode, with \overline{RST} output inactive (in High-Z mode for open-drain option).

3.3 Ground (V_{SS})

This is the ground pin for the device.

3.4 Smart Reset input (\overline{SR})

Push-button Smart Reset input, active low with optional <u>pull-up</u> resistor. \overline{SR} input needs to be asserted for at least t_{SRC} to assert the reset output (RST).

By connecting a voltage higher than V_{CC} + 1.4 V to the \overline{SR} input the device enters test mode (see Section 1: Description on page 3 for more information).

3.5 Reset output (\overline{RST})

RST is active low or active high, open drain or push-pull reset output with optional internal pull-up resistor.

Output reset pulse width is optional as follows:

- Neither fixed nor minimum output reset pulse duration (releasing the push-button while reset output is active, causes the output to de-assert)
- Fixed, factory-programmed output reset pulse duration for t_{REC} independent on Smart Reset input state.

3.6 RST output undervoltage behavior (for open-drain option)

High-Z on \overline{RST} output below the specified operating voltage range is guaranteed at V_{CC} power-on or in case that valid V_{CC} dropped while the device was idle, i.e. while both output and input were inactive.

5//

4 Typical application diagrams

Figure 4. Typical application diagram - input, output and SR1 device in one voltage domain

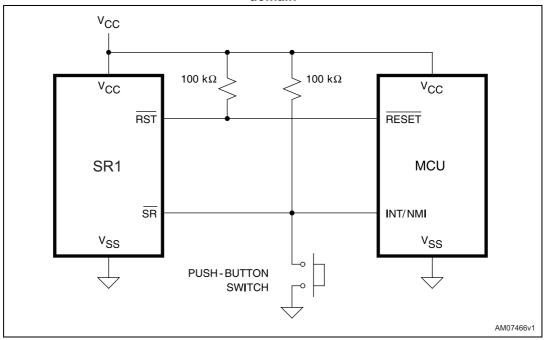
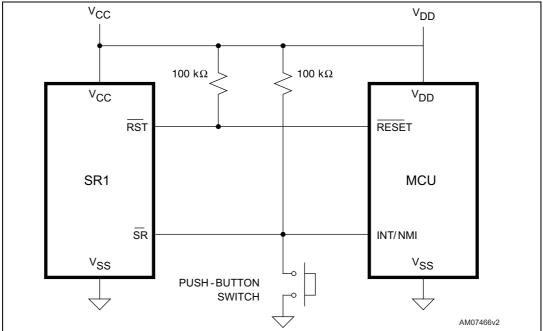


Figure 5. Typical application diagram - SR1 device in a different voltage domain than input and output



Open-drain RST output type and fixed SR input logic threshold allows to use the device in different voltage domains. To prevent entering test mode by creating a condition V(SR) > V_{CC} + 1.1 V typ., V_{CC} should be powered up before or together with voltage on the SR input.



 V_{DD} V_{BAT} 100 nF 🖶 100 kΩ · 100 kΩ VCC V_{DD} RST RESET SR1 MCU SR INT/NMI v_{SS} v_{SS} AM07466v3

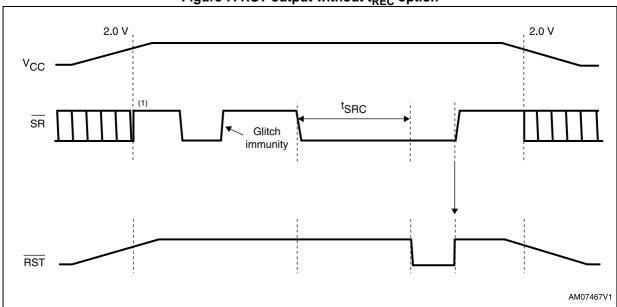
Figure 6. Typical application diagram in different voltage domains - SR input in V_{BAT} domain like V_{CC} totally disables the test mode



SR1 Timing diagrams

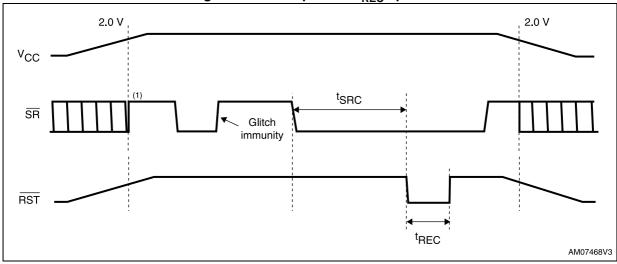
5 Timing diagrams

Figure 7. $\overline{\text{RST}}$ output without t_{REC} option



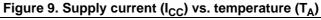
 V_{CC} should be powered up before or together with voltage on the SR input to prevent entering test mode by creating a condition V(SR) > V_{CC} +1.1 V typ.

Figure 8. $\overline{\text{RST}}$ output with t_{REC} option



 V_{CC} should be powered up before or together with voltage on the SR input to prevent entering test mode by creating a condition V(SR) > V_{CC} +1.1 V typ.

6 Typical operating characteristics



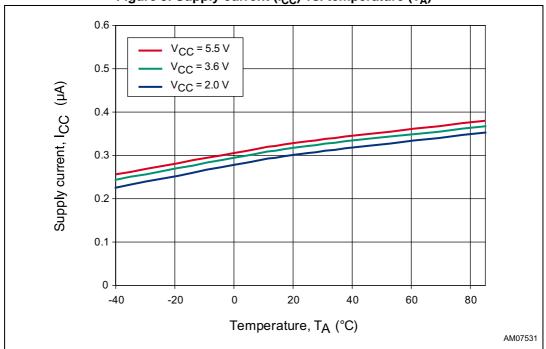
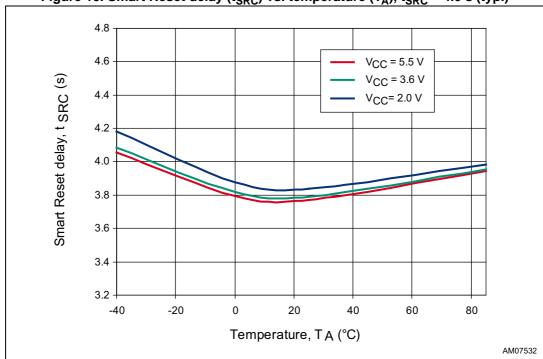


Figure 10. Smart Reset delay (t_{SRC}) vs. temperature (T_A), t_{SRC} = 4.0 s (typ.)



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10/21

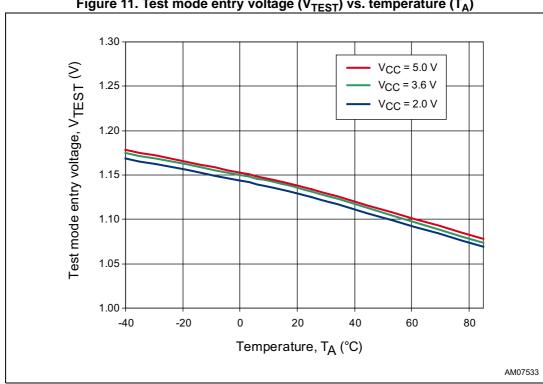
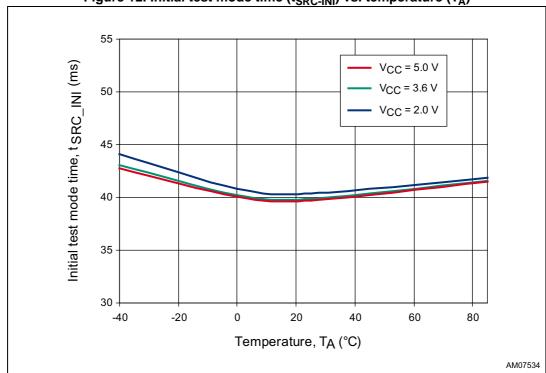


Figure 11. Test mode entry voltage (V_{TEST}) vs. temperature (T_A)





Maximum ratings SR1

7 Maximum ratings

Stressing the device above the rating listed in *Table 2: Absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in *Table 3: Operating and measurement conditions* of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronicsTM SURE program and other relevant quality documents.

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
T _{STG}	Storage temperature (V _{CC} off)	-55 to +150	°C
T _{SLD} ⁽¹⁾	Lead solder temperature for 10 seconds	260	°C
V _{IO}	Input or output voltage	-0.3 to 5.5	V
V _{CC}	Supply voltage	-0.3 to 7	V
ESD			
V _{HBM}	Electrostatic discharge protection, human body model (JESD22-A114-B level 2)	2	kV
V _{RCDM}	Electrostatic discharge protection, charged device model, all pins	1	kV
V _{MM}	Electrostatic discharge protection, machine model, all pins (JESD22-A115-A level A)	200	V
	Latch-up (V _{CC} pin, SR reset input pin)	EIA/JESD78	

^{1.} Reflow at peak temperature of 260 °C. The time above 255 °C must not exceed 30 seconds.



8 DC and AC parameters

This section summarizes the operating measurement conditions, and the DC and AC characteristics of the device. The parameters in *Table 4: DC and AC characteristics* are derived from tests performed under the measurement conditions summarized in *Table 3: Operating and measurement conditions*. Designers should check that the operating conditions in their circuit match the operating conditions when relying on the quoted parameters.

Table 3. Operating and measurement conditions

Symbol	Parameter	Value	Unit
V _{CC}	Supply voltage	2.0 to 5.5	V
T _A	Ambient operating temperature	-40 to +85	°C
t _R , t _F	Input rise and fall times	≤ 5	ns
	Input pulse voltages	0.2 to 0.8 V _{CC}	V
	Input and output timing reference voltages	0.3 to 0.7 V _{CC}	V



Table 4. DC and AC characteristics

Symbol	Parameter	Test conditions ⁽¹⁾	Min.	Typ. ⁽²⁾	Max.	Unit
V _{CC}	Supply voltage		2.0		5.5	V
Icc	Supply current	SR = V _{CC} , t _{REC} and t _{SRC} counter is not running		0.4	1.0	μA
		$V_{CC} \ge 4.5 \text{ V, sinking } 3.2 \text{ mA}$			0.3	V
V _{OL}	Reset output voltage low	$V_{CC} \geq 3.3 \text{ V, sinking } 2.5 \text{ mA}$			0.3	V
		$V_{CC} \ge 2.0 \text{ V, sinking 1 mA}$			0.3	V
4	Reset timeout delay,	(daving option)	140	210	280	ms
t _{REC}	factory-programmed	(device option)	240	360	480	ms
R _{PUO}	Internal out <u>put p</u> ull-up resistor on RST	(device option)		65		kΩ
I _{LO}	Output leakage current	V _{RST} = 5.5 V, open drain device option without output pull-up resistor	-0.1		0.1	μA
Smart Rese	et					
1	Creary Decet dalay	$T_A = -40 \text{ to } +85 ^{\circ}\text{C}$	0.8 x t _{SRC}	4 (3)	1.2 x t _{SRC}	- s
t _{SRC}	Smart Reset delay	T _A = 25 °C	0.9 x t _{SRC}	t _{SRC} ⁽³⁾	1.1 x t _{SRC}	
V _{IL}	SR input voltage low		V _{SS} -0.3		0.3	V
V _{IH}	SR input voltage high		0.85		5.5	V
R _{PUI}	Internal inp <u>ut p</u> ull-up resistor on SR	(device option)		65		kΩ
I _{LEAK}	SR input leakage current	device option without input pull-up resistor	-0.1		0.1	μA
	Input glitch immunity			t _{SRC}		S
Test mode	•					•
V _{TEST}	Test mode entry voltage		V _{CC} +0.9	V _{CC} +1.1	V _{CC} +1.4	V
t _{SRC-INI}	Initial test mode time		28	42	56	ms
t _{SRC-SHORT}	Shortened Smart Reset delay			t _{SRC} / 128		ms

^{1.} Valid for ambient operating temperature T_A = -40 to +85 °C, V_{CC} = 2.0 to 5.5 V.

^{2.} Typical values are at 25 °C and V_{CC} = 3.3 V unless otherwise noted.

^{3.} Factory-programmable in the range of 0.5 s to 10 s typ. in 0.5 s steps.

SR1 Package information

9 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Figure 13. UDFN6, (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch package outline

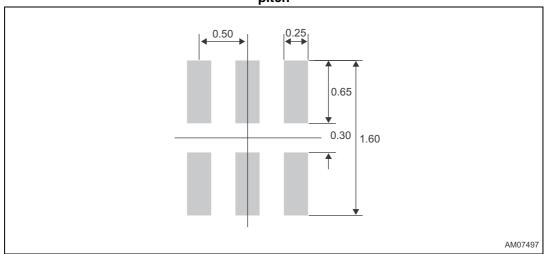
Package information SR1

Table 5. UDFN6, (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch package mechanical data

	Dimensions						
Symbol	(mm)			(inches)			Note ⁽¹⁾
	Min.	Тур.	Max.	Min.	Тур.	Max.	=
Α	0.50	0.55	0.60	0.0197	0.0217	0.0236	
A1	0.00	0.02	0.05	0.000	0.0008	0.0020	
b	0.18	0.25	0.30	0.0071	0.0098	0.0118	
D	1.40	1.45	1.50	0.0551	0.0571	0.0591	
Е	0.95	1.00	1.05	0.0374	0.0394	0.0413	
е	0.45	0.50	0.55	0.0177	0.0197	0.0217	
k	0.20			0.0079			
L	0.30	0.35	0.40	0.0118	0.0138	0.0157	

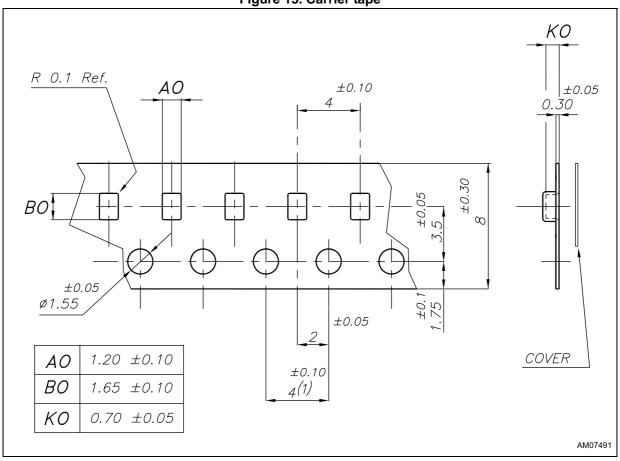
^{1.} Package outline exclusive of any mold flashes dimensions and metal burrs.

Figure 14. Footprint recommendation for UDFN6 (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch



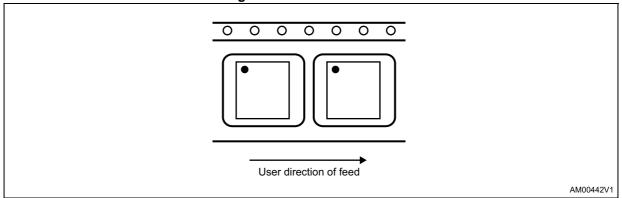
10 Tape and reel information

Figure 15. Carrier tape



1. 10-sprocket hole pitch cumulative tolerance ±0.20.

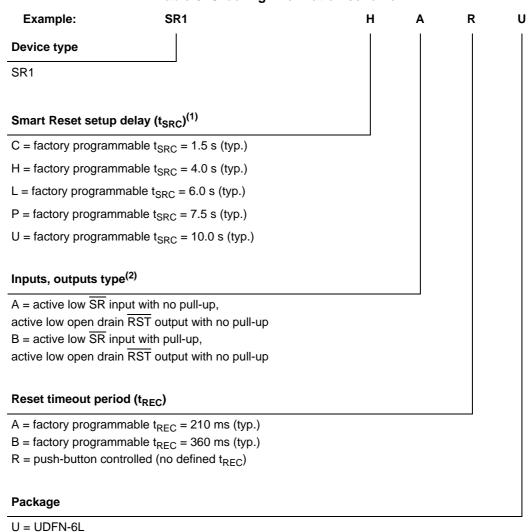
Figure 16. Pin 1 orientation



Part numbering SR1

11 Part numbering

Table 6. Ordering information scheme



Smart Reset delay (t_{SRC}) is available from 0.5 s to 10 s in 0.5 s steps (typ.). Minimum order quantities may apply. Contact local sales office for availability.

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Push-pull reset output type also available (active low or active high). SR input and open drain reset output
available with optional pull-up resistor. Minimum order quantities may apply. Contact local sales office for
availability.

12 Package marking information

Table 7. Package marking

Part number	t _{SRC} (s)	Smart Reset inputs ⁽¹⁾	Output type ⁽²⁾	t _{REC}	Package	Topmark
SR1CARU	1.5	AL	OD, AL	No t _{REC}	UDFN6	CA
SR1HARU	4.0	AL	OD, AL	No t _{REC}	UDFN6	HA
SR1LARU	6.0	AL	OD, AL	No t _{REC}	UDFN6	LA
SR1PAAU	7.5	AL	OD, AL	210 ms	UDFN6	РВ
SR1PARU	7.5	AL	OD, AL	No t _{REC}	UDFN6	PA
SR1PBBU	7.5	AL + pull-up	OD, AL	360 ms	UDFN6	PC
SR1UARU	10.0	AL	OD, AL	No t _{REC}	UDFN6	UA

- 1. AL = active low.
- 2. OD = open drain, AL = active low.
- 3. No t_{REC} = push-button controlled reset pulse width, any other value represents typical value of t_{REC} .

A = dot (pin 1 reference)
B = marking area (topmark)

Revision history SR1

13 Revision history

Table 8. Document revision history

Date	Revision	Changes	
10-Mar-2014	1	Initial release	
13-May-2014	2	Modified t _{REC} values <i>Table 4 on page 14</i>	

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